Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/817,251	LIEN WILEY	
Examiner	Art Unit	
Huyen Le	3751	

SEARCHED					
Class	Subclass	Date	Examiner		
401	21	6/23/2006	HL		
	204 205				
	208 210				
	216 219				
	220 263				
	270 281				
	183				
	updated				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
US-PGPUB		6/23/2006	HL		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
